

*Multiple SiPM readout for EIC calorimeter prototypes, couple of questions for discussion today.*

*Not need to answer these now, probably, not critical for coming test run but at some point we'll need to decide how to proceed.*

*How to select (group) sensors for a single tower?*

*(gain, PDE, temperature dependence, dark noise rate, etc.)*

*(gain, and T dependence adjusted/compensated at FEE)*

*b) PDE, what actually do we measure with the test setup?*

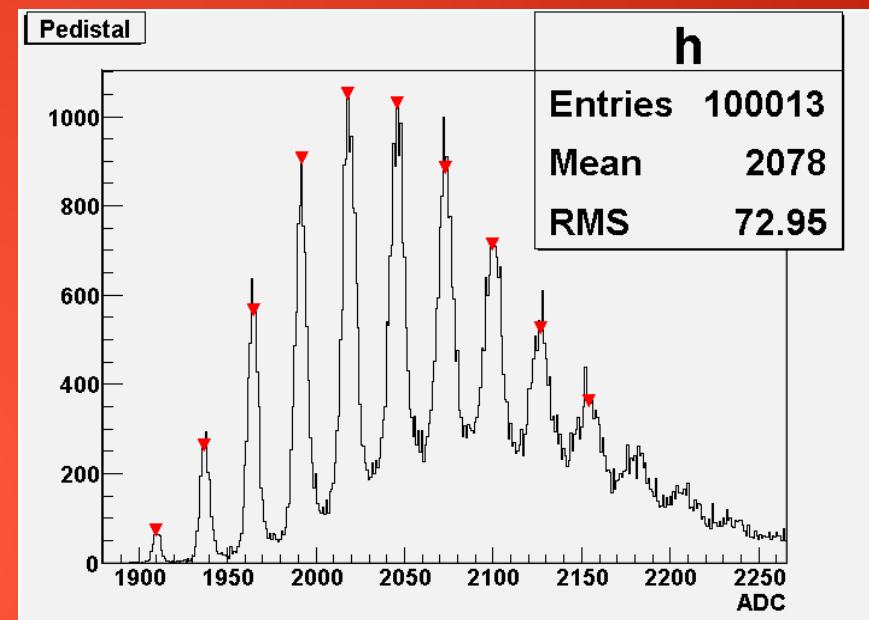
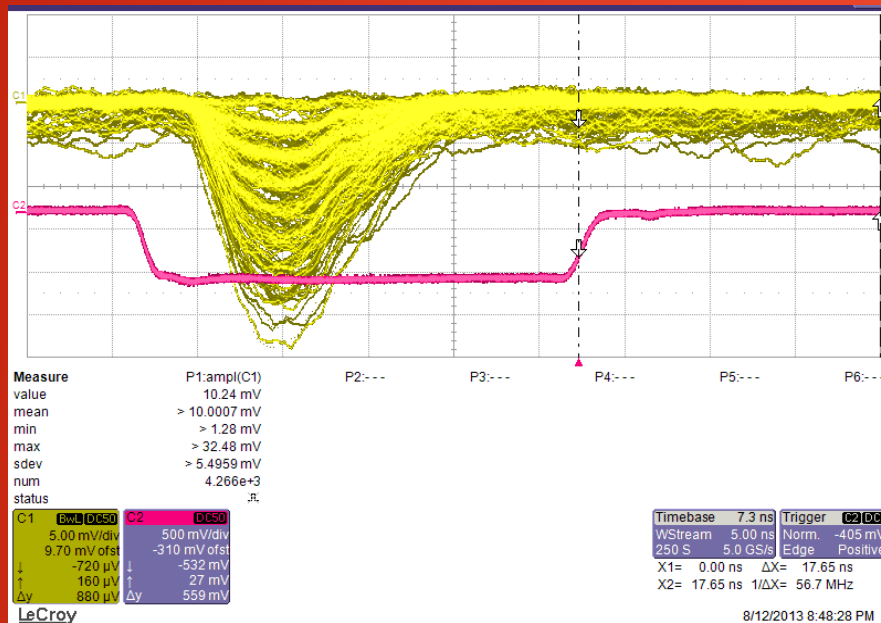
*c) Choice of optimal bias voltage?*

*Adam Lamson (RPI) summer student, supported from EIC R&D funds will tell you about his ongoing SiPM characterization research project here at UCLA.*

08/15/2013

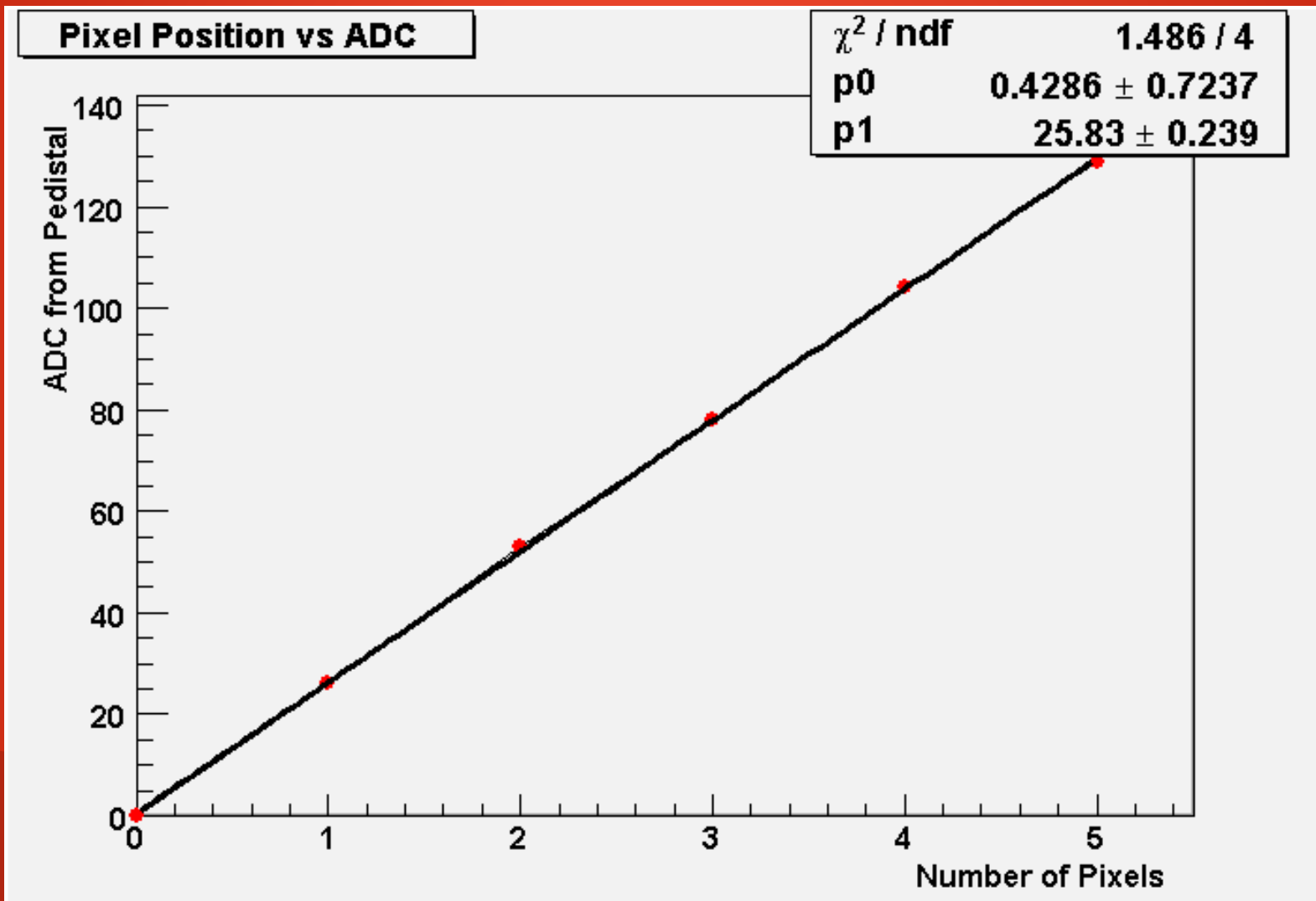
O.Tsai (UCLA)

# SiPM Spectra



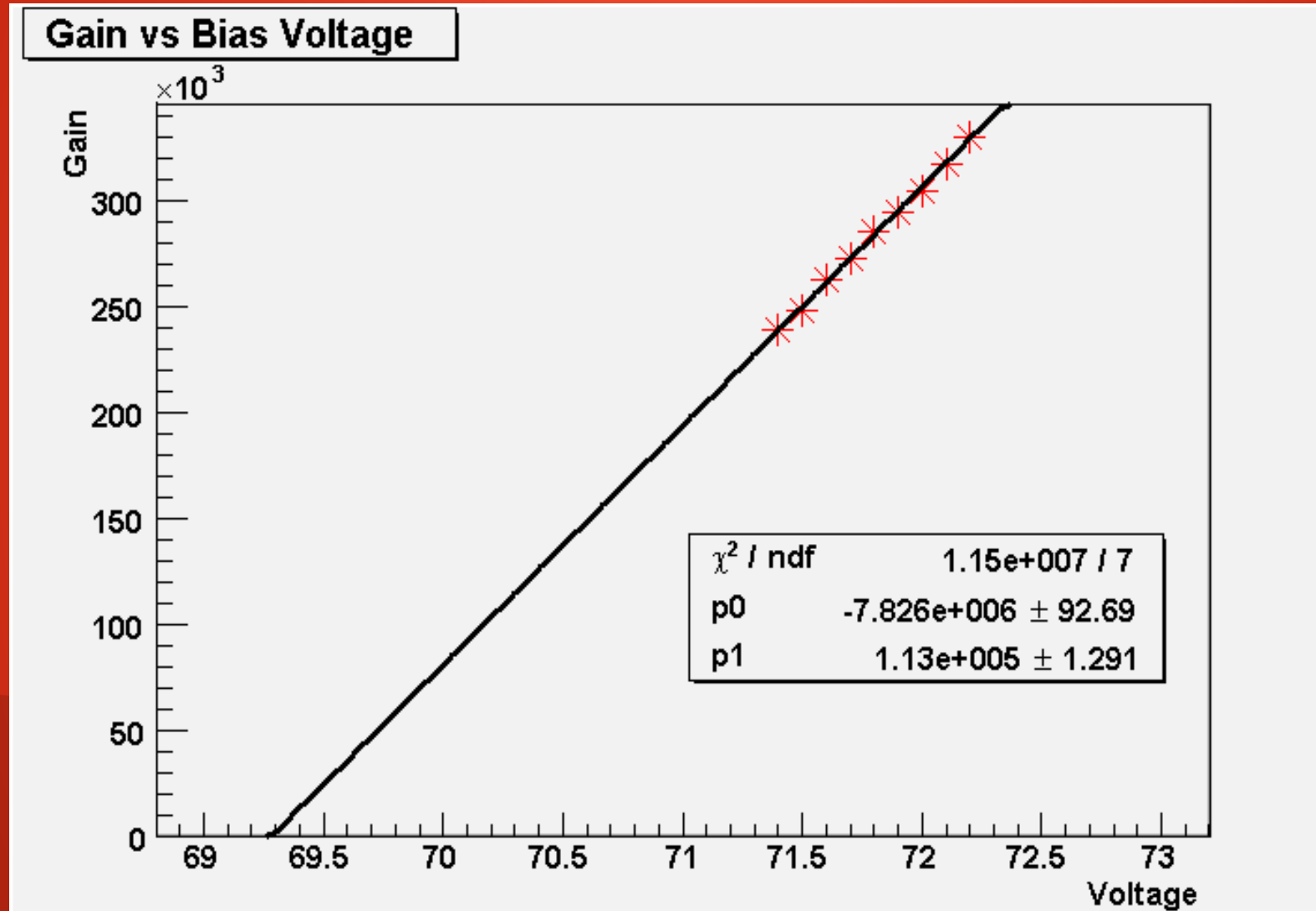
	GLUEX sensors mass testing	Our Sensors
Gate	~120ns	20ns
Breakdown Voltage	~70.4 V	~ 69.3V
Gain	5*10 <sup>5</sup> at 1V above breakdown	Same at 3V above breakdown

# Determining Gain



Gain = Slope of Graph \* Coulombs per ADC /  
Elementary Charge

# Gain Vs Bias and Breakdown Voltage



Breakdown voltage = 69.3 V

# PDE Calculation

How? Calculate Mean number of Photons

Techniques:

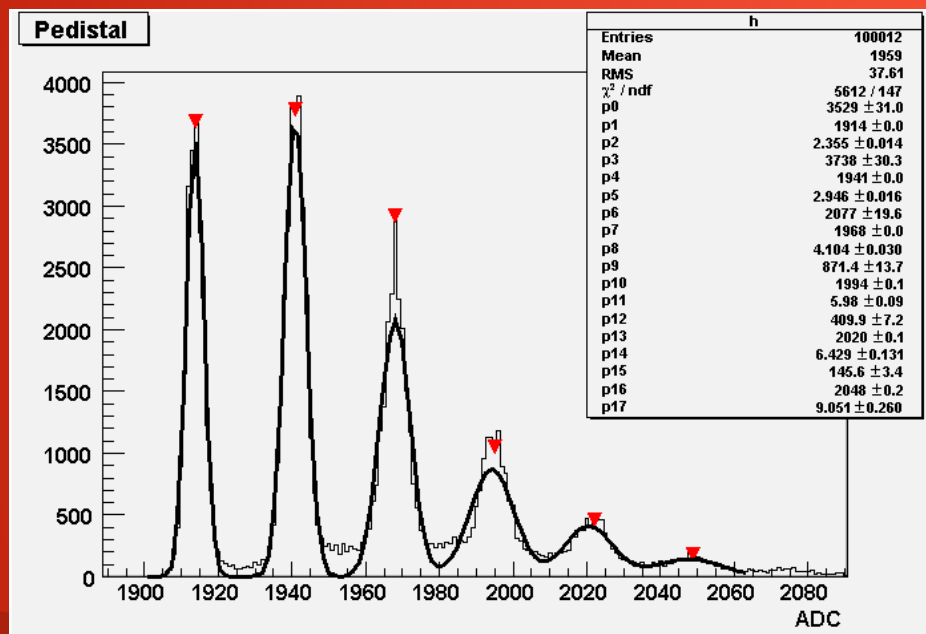
- $\langle N \rangle = \text{Mean} / (\text{ADC per Pixel})$
- Poisson Distribution using probability of no photon

$$\langle N \rangle = -\ln(\text{Prob}(0))$$

- Gluex Method\* (Convolution of two Poisson Distributions)

$$\text{mean} = \langle N \rangle * (1 + \text{OC})$$

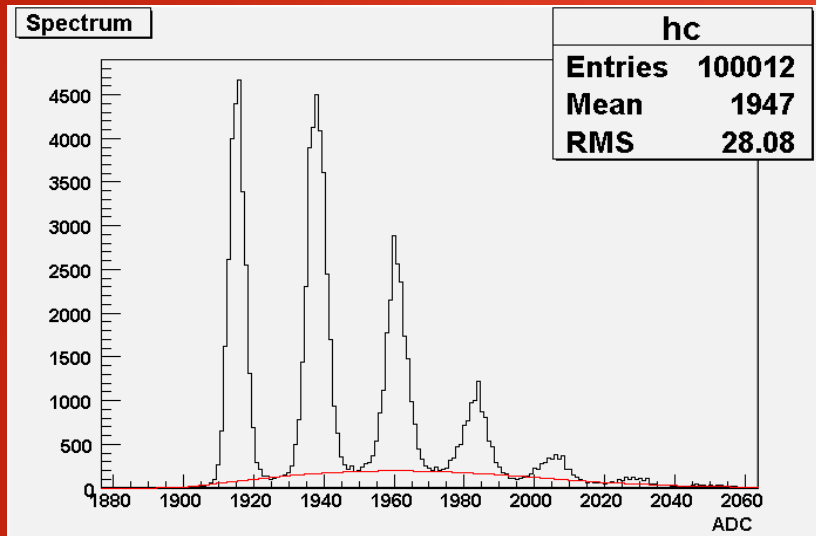
$$\text{var} = \langle N \rangle * (1 + 3\text{OC} + \text{OC}^2)$$



Fitted data but notice inaccuracies and noise.

\*O. Soto, et al., Nuclear Instruments & Methods in Physics Research A (2013), <http://dx.doi.org/10.1016/j.nima.2013.06.071>

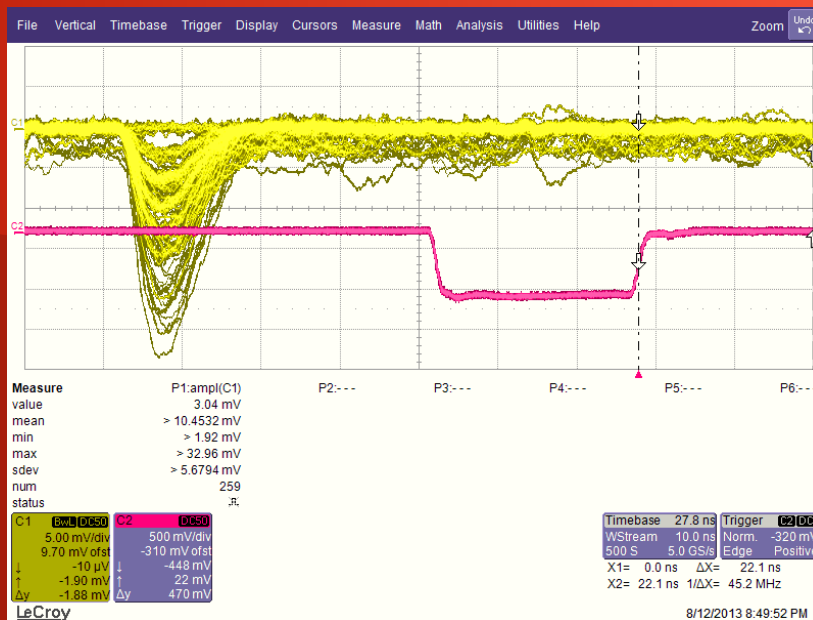
# Background Determination



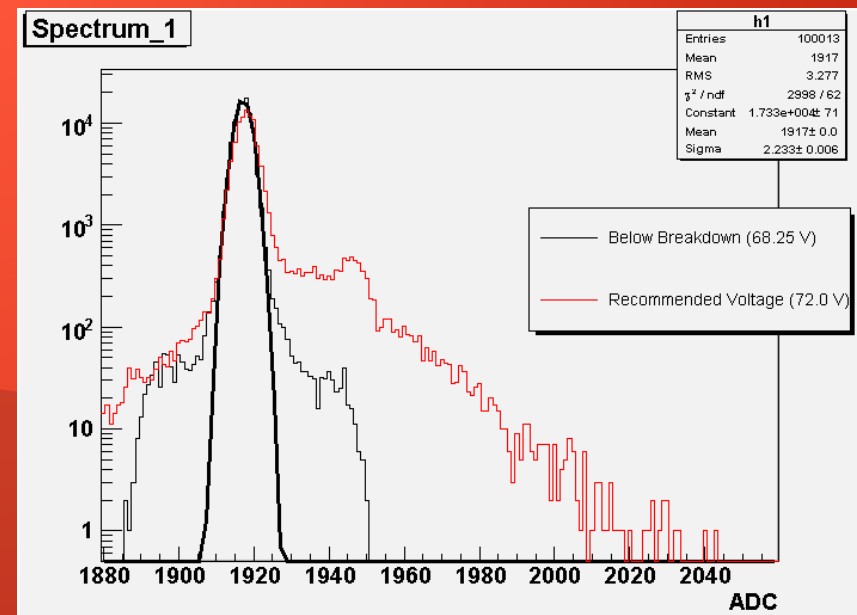
Underlying noise function

## Possible Backgrounds

- Dark Noise
- Optical Crosstalk (OC)
- Afterpulsing

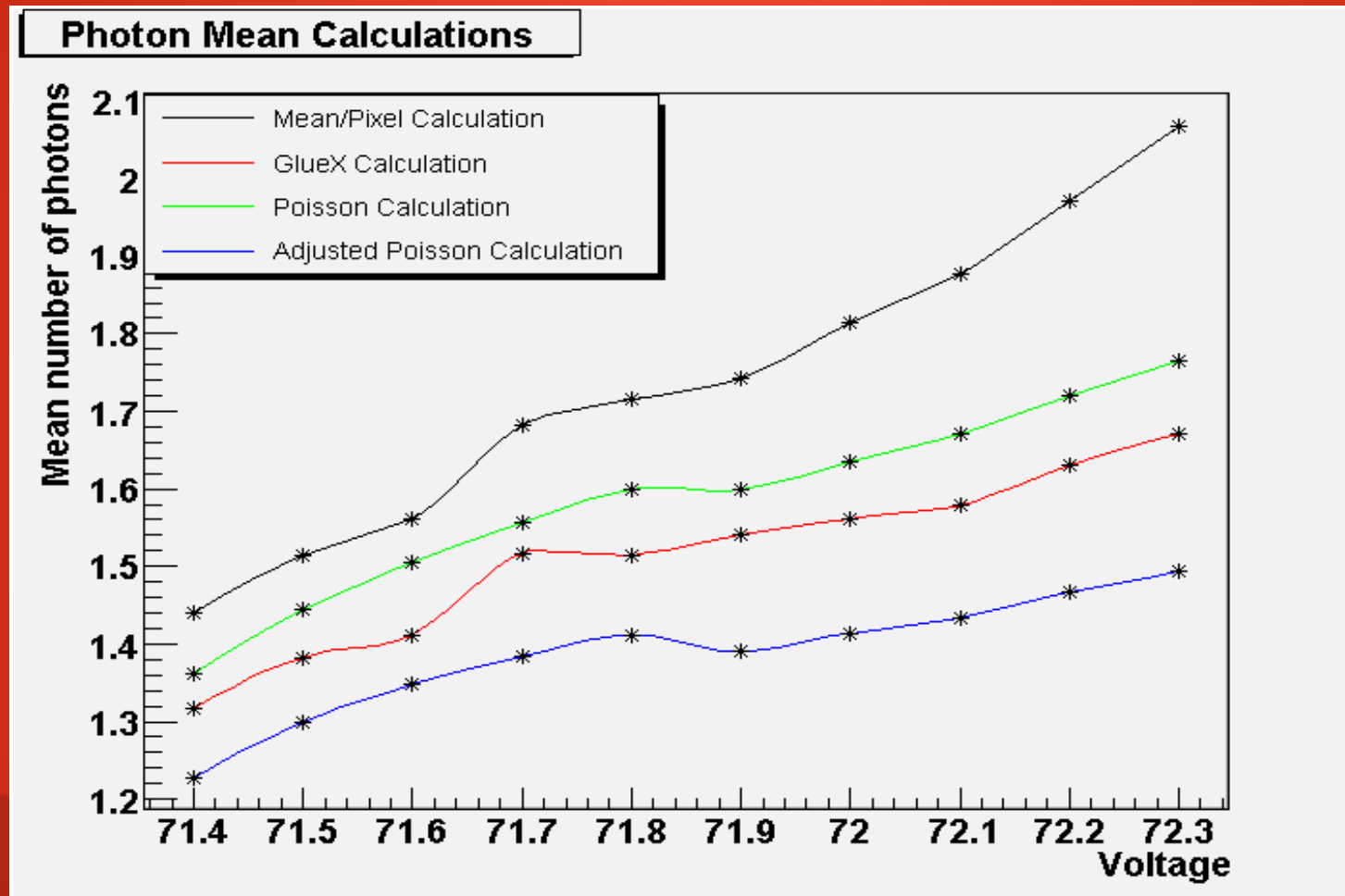


Pulse set before gate to determine dark noise



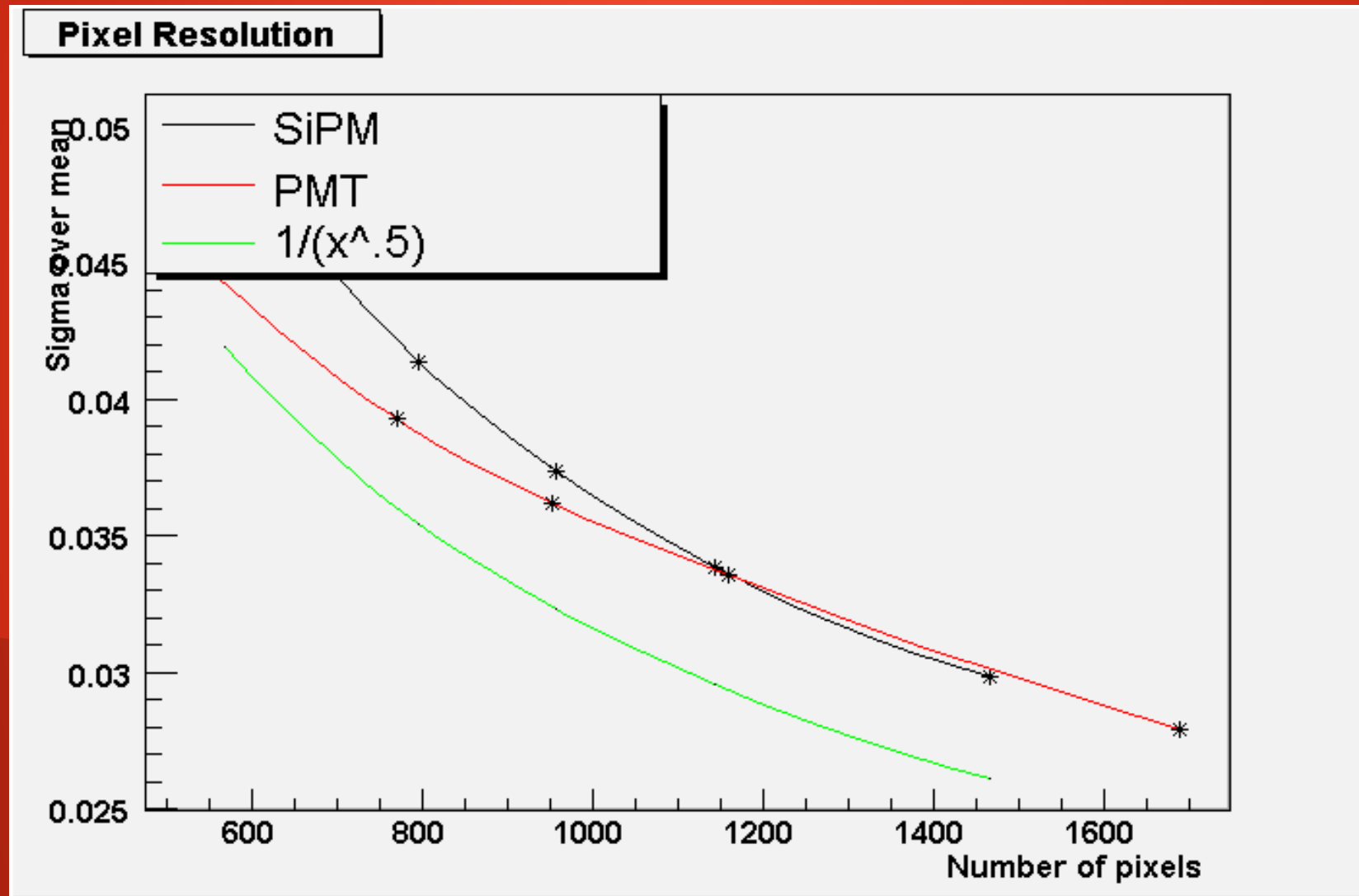
Dark noise comparison above and below breakdown voltage

# PDE Comparisons



Adjusted Probability of Zero = Probability of zero / ( Probability of zero when pulse was outside gate)

# Toward Excess Noise Factor Measurement





# To Do List

1. Measure excess noise factor for MPPC vs bias voltage (question #3)
2. Try to estimate O.C. from dark noise.
3. Dark noise vs bias voltage.
4. May be look at afterpulses if time permit.